

Search Notes



Application/Control No.

10/730,937

Examiner

Tan Dean D. Nguyen

Applicant(s)/Patent under Reexamination

BAIN, DAVID

Art Unit

3629

SEARCHED

Class	Subclass	Date	Examiner
705	1	2/06	DN
	26		
434	107		
700	90		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
I US	2/06	DN
1) Patent		
2) PG Pub		
II FOREIGN		
1. JPO		
2. EPO		
3. Derwent		
4. D		
5. IBM TDOS		